SEM - Carl Zeiss Merlin

Scanning Electron Microscope - Carl Zeiss Merlin

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**Description**

The **Merlin** is a high-resolution Field-Emission Scanning Electron Microscope (FE-SEM) designed for high contrast low-voltage imaging of delicate samples with resolution better than one nanometer. The Merlin has several low-noise backscatter and secondary electron detectors, a novel charging compensation mode, and has become our primary tool for studying soft materials samples such as polymers, nanoparticles, and active biological materials such as patterned silicon nanowires.

**Configuration**

- High-resolution model (40nA)
- Detectors: In-Lens, EsB, AsB, & SE2
- 80mm Airlock
- GIS Charge Compensator (N2)
- IBSS GC10x Plasma Asher
- Spiced SC-20DC

**Training**

Users may request SEM training on the Merlin

**Location**

SEM Lab: GCIS ESB28A

**Contact**

Qiti Guo